Docket: 0756-7272

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re DIVISIONAL application of)	
HONGYONG ZHANG et al.)	
Based on Serial No. 09/222,185)	Group Art Unit: 2826
Filed: December 29, 1998)	Ex.: M. Wilczewski
For: SEMICONDUCTOR DEVICE AND)	
METHOD FOR ITS PREPARATION)	

INFORMATION DISCLOSURE STATEMENT

Commissioner of Patents P.O. Box 1450 Alexandria, Virginia 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56 and 37 C.F.R. 1.97-1.99, Applicant submits herewith a Form PTO-1449 listing references known to Applicant and requests that these references be made of record in the above identified application.

Copies of U.S. patents and U.S. publications are not enclosed in accordance with the Notice published in the Official Gazette on August 5, 2003 entitled *Information Disclosure Statements May Be Filed Without Copies of U.S. Patents and Published Applications in Patent Applications filed after June 30, 2003*, which waives the requirement under 37 CFR 1.98(a)(2)(i) for submitting a copy of each cited U.S. patent and each U.S. publication.

The remaining references listed on the attached Form PTO-1449 were cited in parent application Serial No. 09/222,185, and predecessor Application Serial Nos. 08/911,912 and 08/263,351 and copies of the references can be found in those applications.

Respectfully submitted,

Eric J. Robinson

Reg. No. 38,285

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Substitut	te for form 1449A/PTO			Ci	omplete if Known
INFO	RMATION I	חופרי	LOSURE	Application Number	Based on 09/222,185
	TEMENT BY			Filing Date	December 29, 1998
51A				First Named Inventor	Hongyong ZHANG, et al.
1	(use as many sheets a	as necesso	iry)	Group Art Unit	2822
L				Examiner Name	Mary Wilczewski
Sheet	1	of	4	Attorney Docket Number	0756-7272

				U.S. PATENT DOCUMEN	TS	
Examiner Initials*	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited	Date of Publication of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)	Document	MM-DD-YYYY	
		5,278,093		Yonehara	01/11/94	
•		5,147,826		Liu et al.	09/15/92	
		5,275,851		Fonash et al.	01/04/94	

		F	OREIGN PATENT DOC	UMENTS					
Examiner Initials*	Cite No.	Foreign Patent Document Kind Code ³ Office ³ Number ⁴ (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴			
•	JP	58-068923		04/25/83		Abst.			
	JP	59-028327		02/15/84		Abst			
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	JP	05-082442		04/02/93		Abst			
		OTHER PRIOR	ART – NON PATENT LITE	RATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.)., date, page(s), volume-issue number(s), publisher, city and/or country where published.							
		English Translation of Japanese Patent Office Communication about Claim Rejection of Corresponding Japanese Patent Application							
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		C. Hayzelden et al., "In S Mediated Crystallization			ies of Silicide-				
•		A. V. Dvurechenskii et al			icon Doped by Ion				
		Implantation of 3d Metals							
	<u> </u>	USR, pp. 635-640.							
		T. Hempel et al., "Needle							
		Films," Solid State Communications, Vol. 85, No. 11, pp. 921-924, 1993.							

Examiner	Date	
Signature	Considered	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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SIAI	STATEMENT BY APPLICANT			First Named Inventor	Hongyong ZHANG, et al.
	(use as many sheets o	as necesso	ary)	Group Art Unit	2822
ĺ				Examiner Name	Mary Wilczewski
Sheet	2	of	4	Attorney Docket Number	0756-7272

				U.S. PATENT DOCUMEN	ΓS	
Examiner Initials	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited	Date of Publication of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)	Document	MM-DD-YYYY	
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· ·		5,463,254		Iyer et al.	10/31/95	
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Examiner Initials	Ci te N o.1	Office ³	Foreign Patent Document Kind Code ⁵ Number ⁴ (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T⁴		
		JP	02-140915		05/30/90		Full		
-	İ	JP	02-148831		06/07/90		Abst.		
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		WO	92-01089		01/23/92		Engl.		
			OTHER PR	IOR ART – NON PATENT LITI	ERATURE DOCUMENTS				
Examiner Initials*	Cite No.1		Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.)., date, page(s), volume-issue number(s), publisher, city and/or country where published.						
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		Kak	kad et al., "Low To	emperature Selective Cry Ion-Crystalline Solids, 1	ystallization of Amorp				
		Sub	strates Using Short	line Silicon Thin Film T Time, Low-Temperatur					
	ļ		6, Appl. Phys. Lett		1 0'1'	- 1 T			
			Liu et al., "Selective Area Crystallization of Amorphous Silicon Films by Low- Temperature Rapid Thermal Annealing," August 14, 1989, pp. 660-662, Appl. Phys. Lett						

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Signature	Considered	

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Substitu	e for form 1449A/PTO		c	Complete if Known		
INEC	DMATION	DISCLOSURE	Application Number	Based on 09/222,185		
			Ellina Data	December 29, 1998		
STATEMENT BY APPLICANT			First Named Inventor	Hongyong ZHANG, et al.		
	(use as many sheets	as necessary)	Group Art Unit	2822		
			Examiner Name	Mary Wilczewski		
Sheet	3	of 4	Attorney Docket Number	0756-7272		
	1	1 1				

		##***	U.S. PATENT DOCUMEN	TS	
Examiner Initials*	Cite No.	U.S. Patent Document	Name of Patentee or Applicant of Cited	Date of Publication of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number Kind Code ² (if known)	Document	MM-DD-YYYY	
	ĺ	4,136,434	Thibault et al.	01/30/79	
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				F	OREIGN PATENT DOC	UMENTS			
Examiner Initials*	Cite No.1	Foreign Patent Document		Name of Patentee or	Date of Publication of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant			
		Office ³	Number ⁴	Kind Code ³ (if known)	Applicant of Cited Document	MM-DD-YYYY	Figures Appear	Τ*	
		JP	63-03077	6		02/09/88		Abst.	
<u>-</u>		JР	05-06763	5		03/19/93		Full	
		JP	01-13211	5		05/24/89		Abst.	
			O	THER PRIOR	ART – NON PATENT LITE	RATURE DOCUMENTS			
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.)., date, page(s), volume-issue number(s), publisher, city and/or country where published.						T²	
			Hayzelden et al., "Silicide Formation and Silicide-Mediated Crystallization of Nickel- Implanted Amorphous Silicon Thin Films," J. Appl. Phys., Vol. 73, No. 12, 15 June 1993.						
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Examiner	Date	
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				FO	REIGN PATENT DOC	CUMENTS			
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or	Date of Publication of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant		
		Office ³	Number ⁴	Kind Code ³ (if known)	Applicant of Cited Document	MM-DD-YYYY	Figures Appear	T ⁶	
-		EP	1 026 751			08/09/00		Eng.	
		EP	1 026 752			08/09/00		Eng	
		EP	0 631 325		-	12/28/94		Eng	
		EP	0 631 325			05/07/03		Eng	
			го	HER PRIOR A	RT – NON PATENT LIT	ERATURE DOCUMENTS			
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.)., date, page(s), volume-issue number(s), publisher, city and/or country where published.							
		European Search Report dated October 2, 2002.							
		Communication Pursuant to Article 96(2) EPC, European Patent Office, June 30, 2003.							
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